

May 2001

FQT13N06L

60V LOGIC N-Channel MOSFET

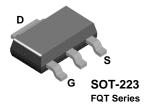
General Description

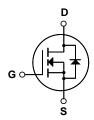
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 2.8A, 60V, $R_{DS(on)}$ = 0.11 Ω @V_{GS} = 10 V Low gate charge (typical 4.8 nC)
- Low Crss (typical 17 pF)
- Fast switching
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

	U				
Symbol	Parameter		FQT13N06L	Units	
V _{DSS}	Drain-Source Voltage		60	V	
I _D	Drain Current - Continuous (T _C = 25°C)		2.8	А	
	- Continuous (T _C = 70°	°C)	2.24	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	11.2	А	
V _{GSS}	Gate-Source Voltage		± 20	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	85	mJ	
I _{AR}	Avalanche Current	(Note 1)	2.8	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	0.21	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns	
P_{D}	Power Dissipation (T _C = 25°C) - Derate above 25°C		2.1	W	
			0.017	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	
٠.			300	C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		60	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	\$	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	l to 25°C		0.05		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V				1	μА
		V _{DS} = 48 V, T _C = 125°C				10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1.0		2.5	V
R _{DS(on)}	Static Drain-Source $V_{GS} = 10 \text{ V}, I_D = 1.4 \text{ A}$				0.088	0.11	Ω
, ,	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 1.4 \text{ A}$			0.110	0.14	52
9FS	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_{D} = 1.4 \text{ A}$	(Note 4)	-	4.1		S
	ic Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			270	350	pF
C _{oss}	Output Capacitance				95	125	pF
C _{rss}	Reverse Transfer Capacitance				17	23	pF
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 6.8 A,	V - 20 V I - 6 9 A		8	25	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		-	90	190	ns
t _{d(off)}	Turn-Off Delay Time	- 11G - 20 22		-	20	50	ns
t _f	Turn-Off Fall Time	=	(Note 4, 5)	-	40	90	ns
Qg	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 13.6 \text{ A},$			4.8	6.4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$ (Note 4, 5)			1.6		nC
Q _{gd}	Gate-Drain Charge				2.7		nC
l _S	Source Diode Characteristics at Maximum Continuous Drain-Source Dio	ode Forward Current	s			2.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	in the second se				11.2	A
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.8 \text{ A}$				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 13.6 \text{ A},$			45		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs	(Note 4)		45		nC

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. L = 12.6mH, I_{AS} = 2.8A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25°C
 3. I_{SD} \leq 13.6A, di/dt \leq 300A/ μ s, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C
 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2%
 5. Essentially independent of operating temperature

Typical Characteristics

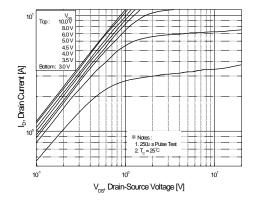


Figure 1. On-Region Characteristics

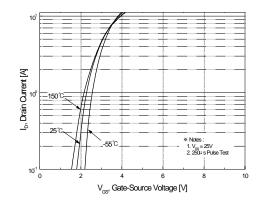


Figure 2. Transfer Characteristics

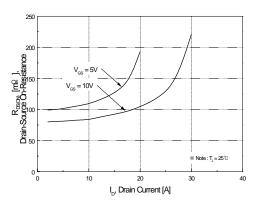


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

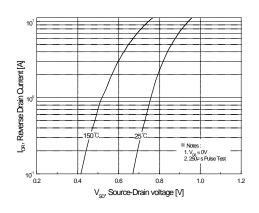


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

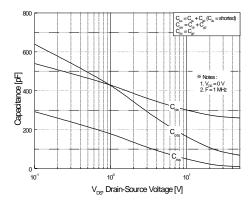


Figure 5. Capacitance Characteristics

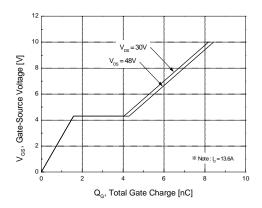


Figure 6. Gate Charge Characteristics

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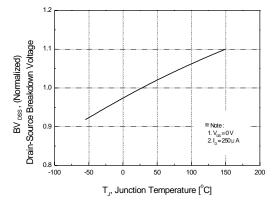


Figure 7. Breakdown Voltage Variation vs Temperature

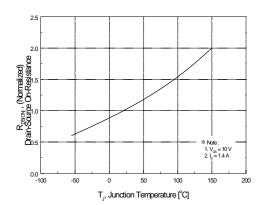


Figure 8. On-Resistance Variation vs Temperature

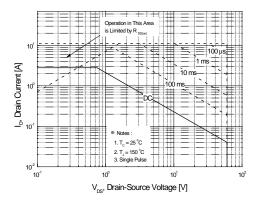


Figure 9. Maximum Safe Operating Area

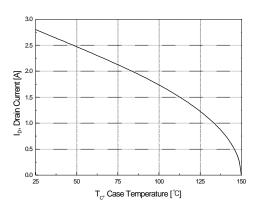


Figure 10. Maximum Drain Current vs Case Temperature

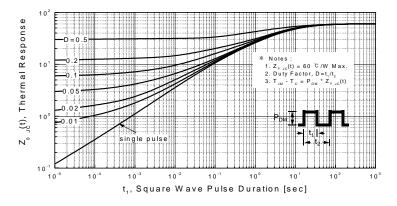
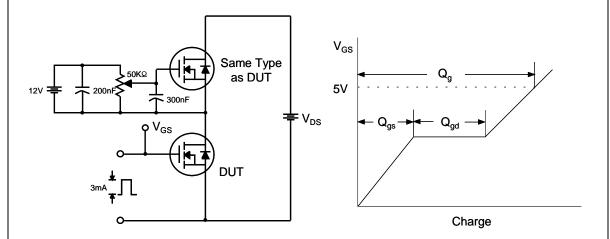


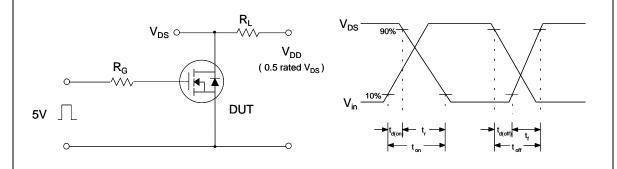
Figure 11. Transient Thermal Response Curve

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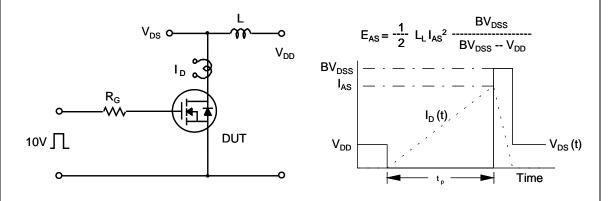
Gate Charge Test Circuit & Waveform



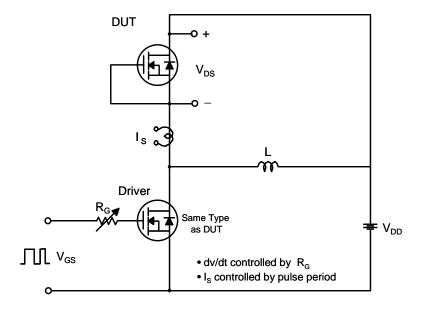
Resistive Switching Test Circuit & Waveforms

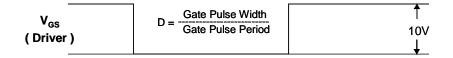


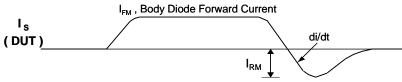
Unclamped Inductive Switching Test Circuit & Waveform



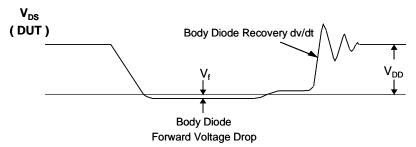
Peak Diode Recovery dv/dt Test Circuit & Waveform





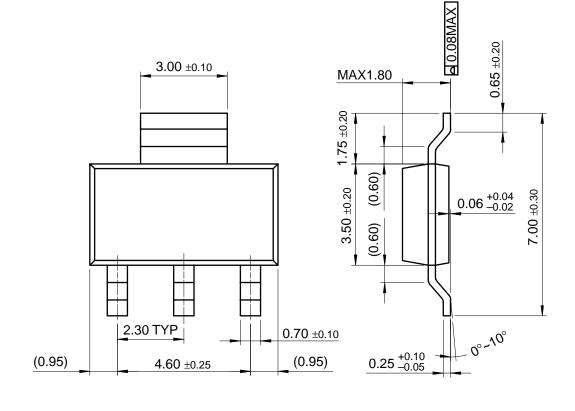


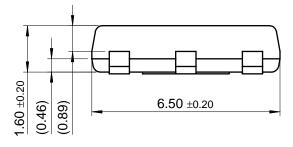
Body Diode Reverse Current





SOT-223





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